

ABSTRACT OF THE DISCLOSURE

A semiconductor testing apparatus and a semiconductor testing method are provided which permit an apparatus having an inexpensive configuration to perform, with precision, the acceptance-or-rejection determination and measurement test of a semiconductor integrated circuit having a large number of output terminals each for outputting a multi-gradation level output voltage. The semiconductor testing apparatus comprises output voltage testing means and comparison voltage generation data inputting means. The output voltage testing means comprises test voltage inputting means, comparison voltage generating means, a high level comparator, a low level comparator, and comparison result outputting means. The high level comparator and the low level comparator constitute comparing means for comparing a voltage to be tested, with a comparison voltage.